Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/734,870	LEEK ET AL.	
Examiner	Art Unit	
Jeanette E. Chapman	3633	

	SEARCHED				
Class	Subclass	Date	Examiner		
SEARCH	UPDATED	12/28/2009	JC		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH (INCLUDING SEAF	NOTES RCH STRATEGY	)
	DATE	EXMR
INVENTOR SEARCH	12/28/2009	JC